

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/670,354	NIWA, TAKEO	
Examiner	Stephen J Stein	Art Unit	1775

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	A	US-4,357,526	11-1982	Yamamoto et al.	219/544
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	U	
	V	
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